MOSFET - Power, Single, N-Channel, SO-8 FL 30 V, 147 A

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

Applications

• CPU Power Delivery, DC-DC Converters

MAXIMUM RATINGS ($T_J = 25^{\circ}C$ unless otherwise stated)

Parai	Parameter			Value	Unit
Drain-to-Source Voltage			V_{DSS}	30	V
Gate-to-Source Voltage			V_{GS}	±20	V
Continuous Drain Current R _{0JA}			I _D	29.1 18.4	Α
(Note 1)		, ,	_		
Power Dissipation $R_{\theta JA}$ (Note 1)		T _A = 25°C	P _D	2.72	W
Continuous Drain Current $R_{\theta,IA} \le 10 \text{ s}$		T _A = 25°C	Ι _D	47.5	Α
(Note 1)		T _A = 100°C		30.0	
Power Dissipation $R_{\theta JA} \le 10 \text{ s (Note 1)}$	Steady	T _A = 25°C	P _D	7.23	W
Continuous Drain	State	T _A = 25°C	I _D	17.1	Α
Current $R_{\theta JA}$ (Note 2)		T _A = 100°C		10.8	
Power Dissipation $R_{\theta JA}$ (Note 2)		T _A = 25°C	P _D	0.93	W
Continuous Drain		T _C = 25°C	I _D	147	Α
Current R _{θJC} (Note 1)		T _C =100°C		93	
Power Dissipation R _{θJC} (Note 1)		T _C = 25°C	P _D	69.44	W
Pulsed Drain Current	$T_{A} = 25^{\circ}$	C, t _p = 10 μs	I _{DM}	442	Α
Current Limited by Pac	kage	T _A = 25°C	I _{Dmax}	100	Α
Operating Junction and Storage Temperature			T _J , T _{STG}	–55 to +150	°C
Source Current (Body Diode)			I _S	68	Α
Drain to Source DV/DT			dV/d _t	6	V/ns
Single Pulse Drain-to-Source Avalanche Energy T_J = 25°C, V_{DD} = 24 V, V_{GS} = 10 V, I_L = 37 A_{pk} , L = 0.3 mH, R_G = 25 Ω			E _{AS}	205	mJ
Lead Temperature for S (1/8" from case for 10 s	TL	260	°C		

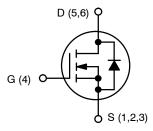
Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.



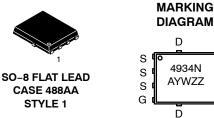
ON Semiconductor®

http://onsemi.com

V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
30 V	2.0 mΩ @ 10 V	447.0
30 V	3.0 m Ω @ 4.5 V	147 A



N-CHANNEL MOSFET



DIAGRAM

D

= Assembly Location

= Year W = Work Week = Lot Traceability

ORDERING INFORMATION

Device	Package	Shipping [†]
NTMFS4934NT1G	SO-8 FL (Pb-Free)	1500 / Tape & Reel
NTMFS4934NT3G	SO-8 FL (Pb-Free)	5000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

1. 2.	Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu. Surface-mounted on FR4 board using the minimum recommended pad size.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	1.8	
Junction-to-Ambient - Steady State (Note 3)	$R_{\theta JA}$	46.0	°C/W
Junction-to-Ambient - Steady State (Note 4)	$R_{\theta JA}$	134.2	°C/VV
Junction-to-Ambient - (t ≤ 10 s) (Note 3)	$R_{\theta JA}$	17.3	

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	•						
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D$	= 250 μΑ	30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /				15.2		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V,	T _J = 25°C			1.0	μΑ
		$V_{DS} = 24 \text{ V}$	T _J = 125°C			10	
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _G	_S = ±20 V			±100	nA
ON CHARACTERISTICS (Note 5)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_{D}$	= 250 μΑ	1.2	1.6	2.2	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				4.6		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 30 A		1.52	2.0	
			I _D = 15 A		1.52		mΩ
		V _{GS} = 4.5 V	I _D = 30 A		2.2	3.0	
			I _D = 15 A		2.2		
Forward Transconductance	9FS	V _{DS} = 1.5 V, I _D = 15 A			80		S
CHARGES, CAPACITANCES & GATE RESIS	TANCE						
Input Capacitance	C _{ISS}				5505		
Output Capacitance	C _{OSS}	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 15 V			2355		pF
Reverse Transfer Capacitance	C _{RSS}				90		1
Total Gate Charge	Q _{G(TOT)}				34		
Threshold Gate Charge	Q _{G(TH)}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}; I_D = 30 \text{ A}$			3.8		nC
Gate-to-Source Charge	Q_{GS}				13.9		
Gate-to-Drain Charge	Q_{GD}				8.1		
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 10 V, V _{DS} = 15 V; I _D = 30 A			76.5		nC
SWITCHING CHARACTERISTICS (Note 6)					•	•	
Turn-On Delay Time	t _{d(ON)}	V_{GS} = 4.5 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω			20.0		ns
Rise Time	t _r				36.2		
Turn-Off Delay Time	t _{d(OFF)}				39.3		
Fall Time	t _f				9.4		

Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
 Surface-mounted on FR4 board using the minimum recommended pad size.

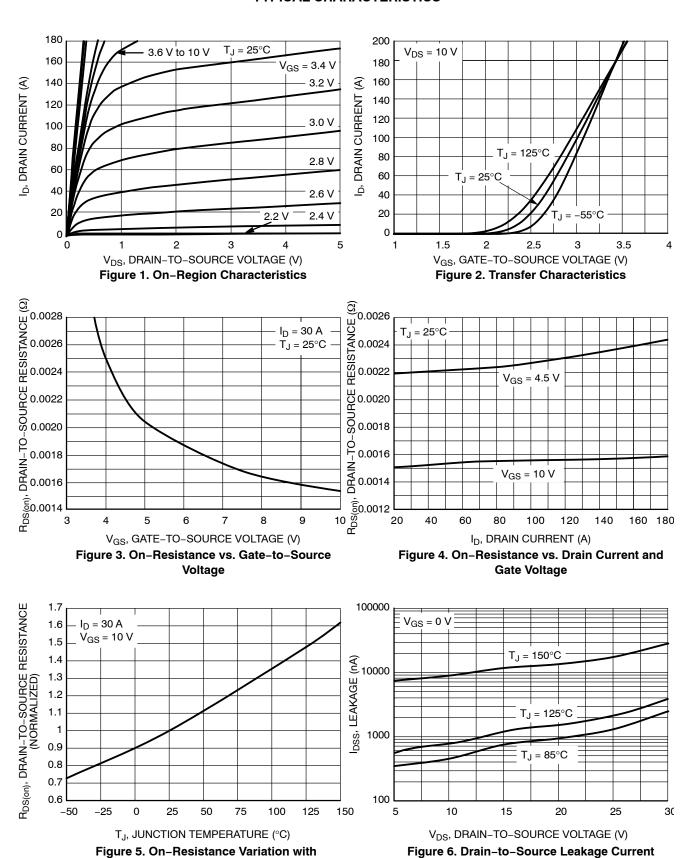
^{5.} Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
6. Switching characteristics are independent of operating junction temperatures.

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (No	ote 6)						
Turn-On Delay Time	t _{d(ON)}			13.2			
Rise Time	t _r	V _{GS} = 10 V, V _{DS} = 1	V_{GS} = 10 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω		33.3		
Turn-Off Delay Time	t _{d(OFF)}	R _G = 3.0	Ω		49.7		ns
Fall Time	t _f	1			7.8		1
DRAIN-SOURCE DIODE CHARACTE	RISTICS						
Forward Diode Voltage	V _{SD}	$V_{GS} = 0 \text{ V},$ $T_J = 25^{\circ}\text{C}$			0.79	1.0	\ /
	I _S = 30 A	T _J = 125°C		0.66		V	
Reverse Recovery Time	t _{RR}	•			59.1		
Charge Time	t _a	$V_{GS} = 0 \text{ V, dIS/dt}$	Vos = 0 V. dIS/dt = 100 A/us.		28.3		ns
Discharge Time	t _b	$V_{GS} = 0 \text{ V, dIS/dt} = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 30 \text{ A}$			30.8		
Reverse Recovery Charge	Q _{RR}				70		nC
PACKAGE PARASITIC VALUES	-						
Source Inductance	L _S				1.00		nΗ
Drain Inductance	L _D	T _A = 25°C			0.005		nΗ
Gate Inductance	L _G				1.84		nΗ
Gate Resistance	R_{G}				0.80		Ω

^{5.} Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
6. Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS



vs. Voltage

Temperature

TYPICAL CHARACTERISTICS

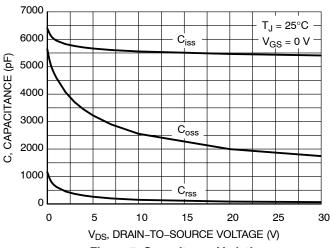


Figure 7. Capacitance Variation

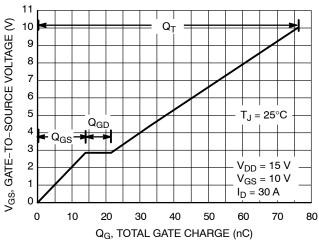


Figure 8. Gate-To-Source and Drain-To-Source
Voltage vs. Total Charge

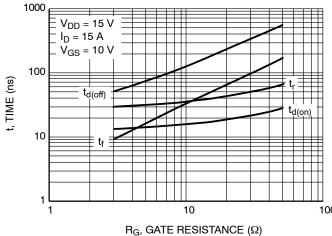


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

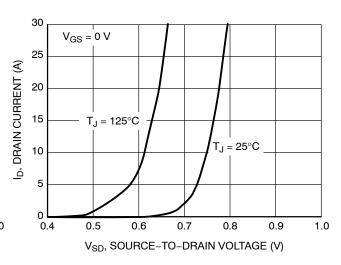


Figure 10. Diode Forward Voltage vs. Current

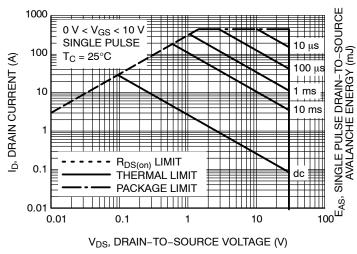
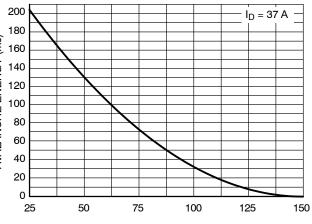


Figure 11. Maximum Rated Forward Biased Safe Operating Area



 $T_{J},\,STARTING\,JUNCTION\,TEMPERATURE\,(^{\circ}C)$

Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

TYPICAL CHARACTERISTICS

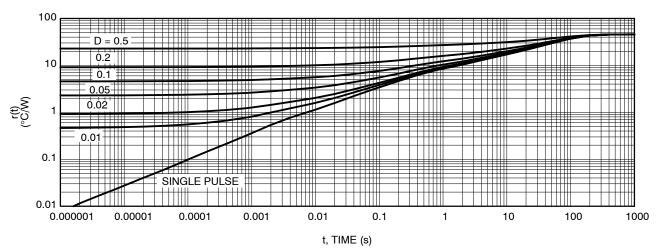


Figure 13. Thermal Response

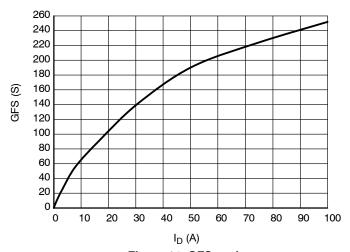
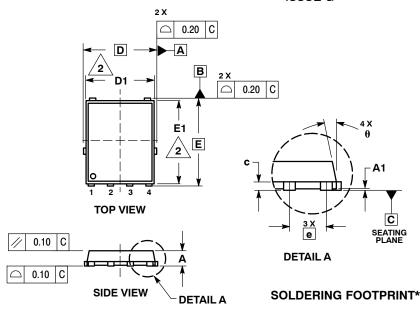


Figure 14. GFS vs. $I_{\rm D}$

PACKAGE DIMENSIONS



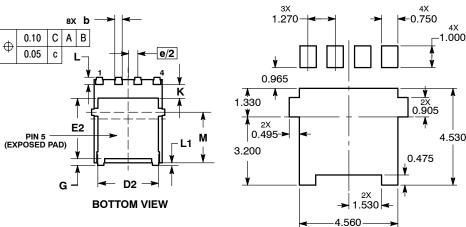


NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994
- CONTROLLING DIMENSION: MILLIMETER. DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE

	MILLIMETERS			
DIM	MIN	NOM	MAX	
Α	0.90	1.00	1.10	
A1	0.00		0.05	
b	0.33	0.41	0.51	
С	0.23	0.28	0.33	
D		5.15 BSC	;	
D1	4.50	4.90	5.10	
D2	3.50		4.22	
E		6.15 BSC	;	
E1	5.50	5.80	6.10	
E2	3.45		4.30	
е		1.27 BSC	;	
G	0.51	0.61	0.71	
K	1.20	1.35	1.50	
L	0.51	0.61	0.71	
L1	0.05	0.17	0.20	
М	3.00	3.40	3.80	
θ	0 °		12 °	

- STYLE 1: PIN 1. SOURCE
 - SOURCE
 SOURCE
 - GATE
 - 5. DRAIN



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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